

REMARKS/ARGUMENTS

The Examiner is thanked for the thorough examination of this application and the allowance of claims 9-12. Claims 1-3, 5-12, and 24-26, however, have been rejected. For at least the reasons that follow, Applicants respectfully request reconsideration and withdrawal of the rejections.

Independent claim 1 is amended by adding the limitations of the conductive loop defining a conductive path having a plurality of sections, and the sections having at least two different alternating widths as measured across the conductive path.

Independent claim 5 is amended by adding the limitations of the conductive loop defining a conductive path having a plurality of sections, and the sections having at least two different alternating widths as measured across the conductive path.

Independent claim 24 is amended by adding the limitations of the conductive loop defining a conductive path having a plurality of sections, and the sections having at least two different alternating widths as measured across the conductive path.

It is respectfully submitted that these amendments do not raise any new issues and should be entered, as the substance of the added subject matter was previously embodied (effectively) in claim 9 (allowed).

35 U.S.C. 102(b)

Claims 1, 5, 8 and 24 were rejected under 35 U.S.C. 102(e) as allegedly anticipated by Blish et al. (U.S. 6,362,524).

Claim 1 recites a method of fabricating an integrated circuit seal ring comprising providing an active area including semiconductor device structures; and forming a continuous conductive

loop around the perimeter of said integrated circuit, the conductive loop defining a conductive path having a plurality of sections, the sections having at least two different alternating widths as measured across the conductive path, wherein each of said sections has a different width from its adjacent sections, wherein characteristic impedance of each of said two different widths is different, wherein said conductive loop forms said seal ring.

Blish does not teach or suggest the conductive loop defines *a conductive path having a plurality of sections*, and the sections having at least two different alternating widths *as measured across the conductive path*, and *each of said sections has a different width from its adjacent sections*.

In Blish, the sections (legs 122) on a conductive path are of similar width (*as measured across the conductive path*) and length (*as measured along the conductive path*) (see column 4, lines 36-37, and FIG. 12), not have different widths from their adjacent sections.

In addition, Applicants respectfully asserts that claim 1 has been misinterpreted. In section 2, the Office Action states that FIG. 12 of Blish discloses that the protruding portions are wider than their adjacent portions. However, the term “width” has been used in accordance with its common and ordinary meaning, i.e. “width” means *across* the conductive loop. In contrast, the office action appears to be referring to the length of the section of Blish for rejecting Claim 1. Applicant respectfully asserts that this is an improper use of Blish because “length” means *along* the conductive loop. Thus, Blish does not teach or suggest the sections in FIG. 12 have different widths from their adjacent sections.

For at least this reason, claim 1 is allowable over the cited reference.

Insofar as claim 1 is allowable, claims 2 and 3, all depend from claim 1 and its related claims, including every claimed element thereof, are also allowable on their own merits in claiming additional elements not included in claim 1.

Independent claim 5 recites a method of fabricating an integrated circuit seal ring comprising: providing an active area including semiconductor device structures; and forming a continuous conductive loop around the perimeter of said integrated circuit by patterning and forming a plurality of stacked, interconnected, conductive layers, the conductive loop defining a conductive path having a plurality of sections, the sections having at least two different alternating widths as measured across the conductive path, wherein each of said sections has a different width from its adjacent sections, wherein said conductive loop forms said seal ring.

Blish does not teach or suggest the conductive loop defines *a conductive path having a plurality of sections*, and the sections having at least two different alternating widths *as measured across the conductive path*, and *each of said sections has a different width from its adjacent sections*.

In Blish, the sections (legs 122) on a conductive path are of similar width (*as measured across the conductive path*) and length (*as measured along the conductive path*) (see column 4, lines 36-37, and FIG. 12), not have different widths from their adjacent sections.

For at least this reason, claim 5 is allowable over the cited reference.

Insofar as claim 5 is allowable, claims 6-8, all depend from claim 5 and its related claims, including every claimed element thereof, are also allowable on their own merits in claiming additional elements not included in claim 5.

Independent claim 24 recites a method of fabricating an integrated circuit seal ring comprising: providing an active area including semiconductor device structures; and forming a continuous conductive loop around the perimeter of said integrated circuit by forming and patterning a plurality of stacked, interconnected, conductive layers, conductive loop defining a conductive path having a plurality of sections, the sections having at least two different alternating widths as measured across the conductive path, wherein said conductive loop forms said seal ring.

Blish does not teach or suggest the conductive loop defines *a conductive path having a plurality of sections*, and the sections having at least two different alternating widths *as measured across the conductive path*.

In Blish, the sections (legs 122) on a conductive path are of similar width (*as measured across the conductive path*) and length (*as measured along the conductive path*) (see column 4, lines 36-37, and FIG. 12), not have different widths from their adjacent sections.

For at least this reason, claim 24 is allowable over the cited reference.

Insofar as claim 24 is allowable, claims 25 and 26, all depend from claim 24 and its related claims, including every claimed element thereof, are also allowable on their own merits in claiming additional elements not included in claim 24.

Conclusion

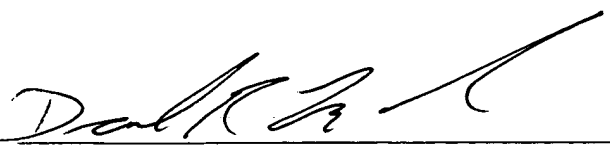
For at least the reasons described above, claims 1, 5 and 24 are allowable over the cited references. Insofar as these independent claims are allowable, all dependent claims are allowable as well.

Reconsideration and withdrawal of the rejections is respectfully requested. Applicant has made every effort to place the present application in condition for allowance. It is therefore earnestly requested that the present application, as a whole, receive favorable consideration and that all of the claims be allowed in their present form.

Should Examiner feel that further discussion of the application and the Amendment is conducive to prosecution and allowance thereof, please do not hesitate to contact the undersigned at the address and telephone listed below.

No fee is believed to be due in connection with this amendment and response to Office Action. If, however, any fee is believed to be due, you are hereby authorized to charge any such fee to deposit account No. 20-0778.

Respectfully submitted,

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